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FIG. 1

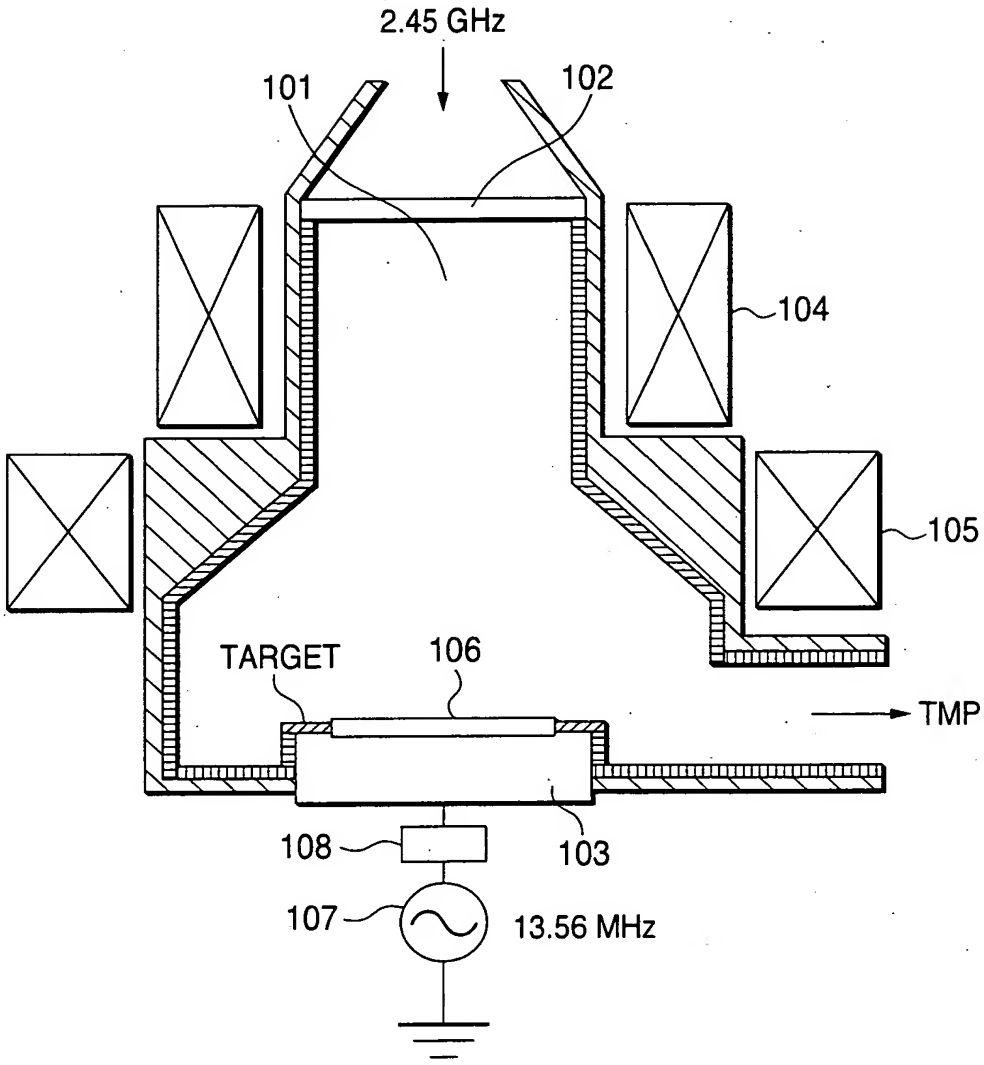

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FIG. 2A

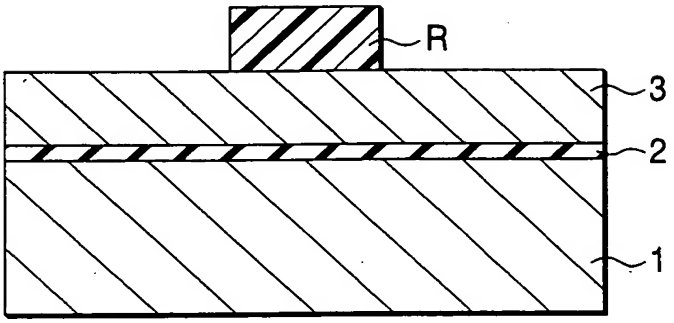


FIG. 2B

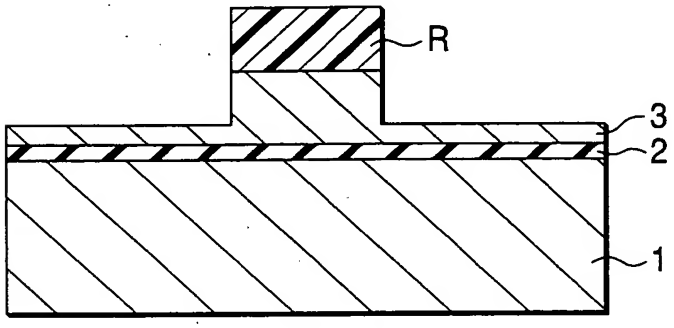


FIG. 2C

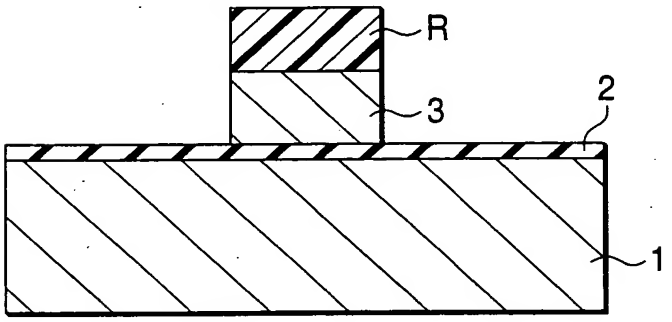

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FIG. 3

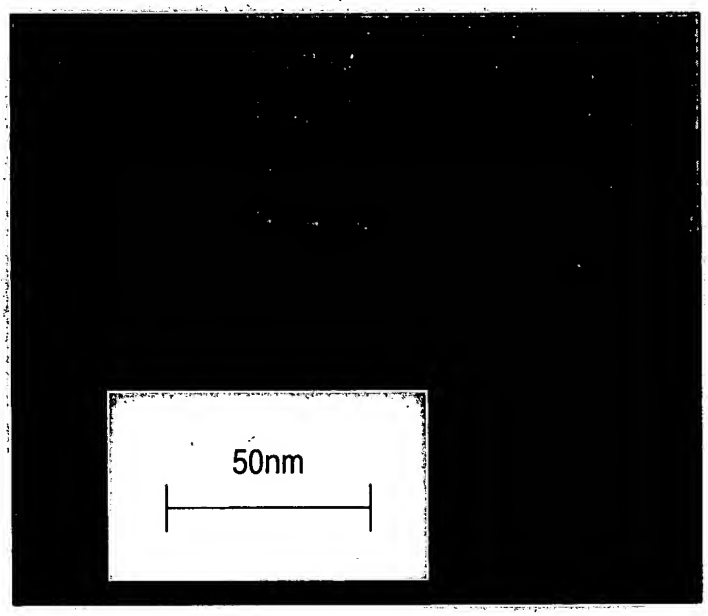


FIG. 4

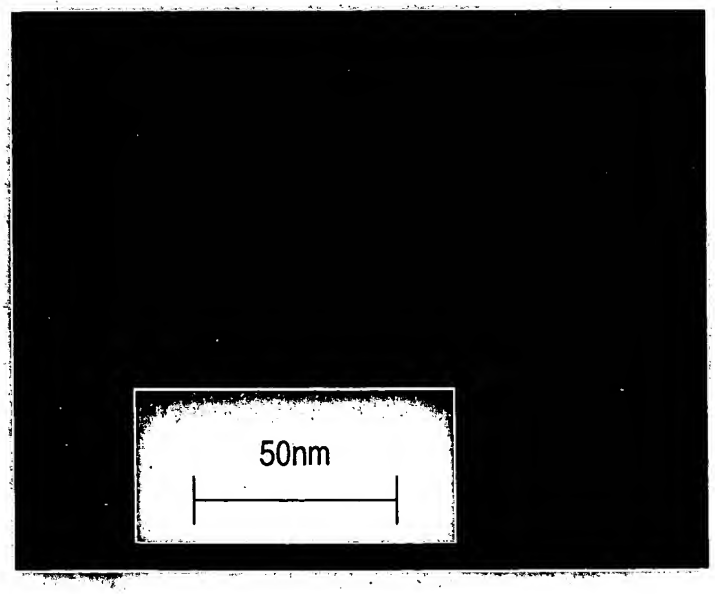

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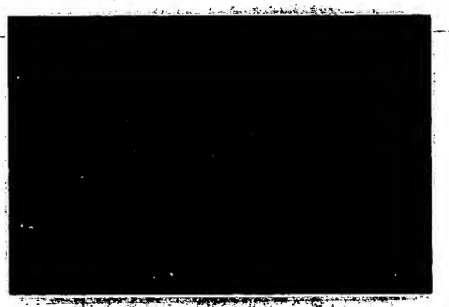
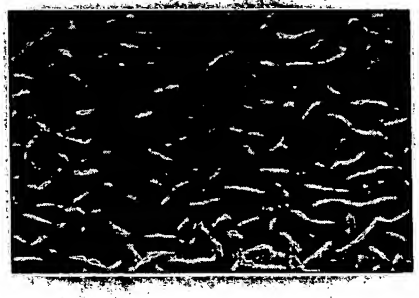
FIG. 5

FIG. 6A



PARTIALLY ETCHED polySi

FIG. 6B



GATE OXIDE SURFACE
SURFACE MORPHOLOGY OF polySi AND GATE OXIDE

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FIG. 7

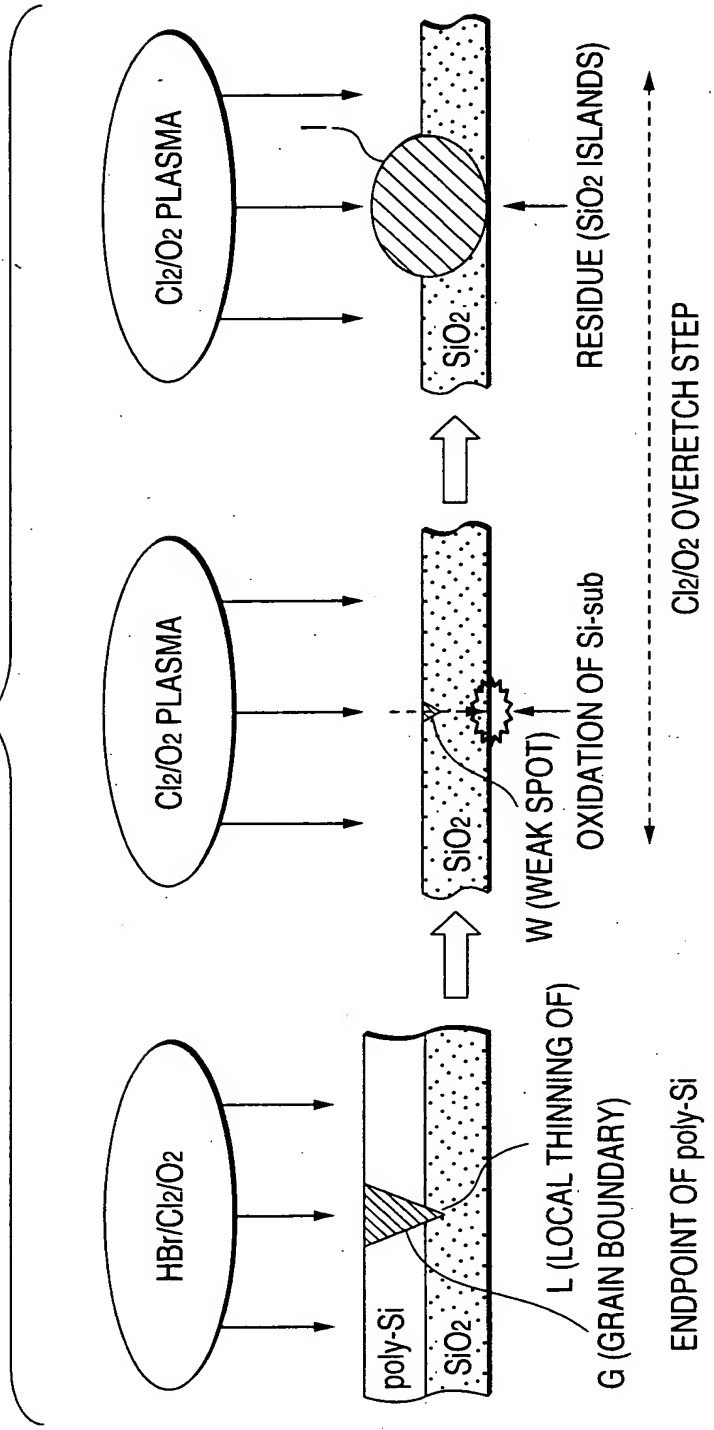

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FIG. 8

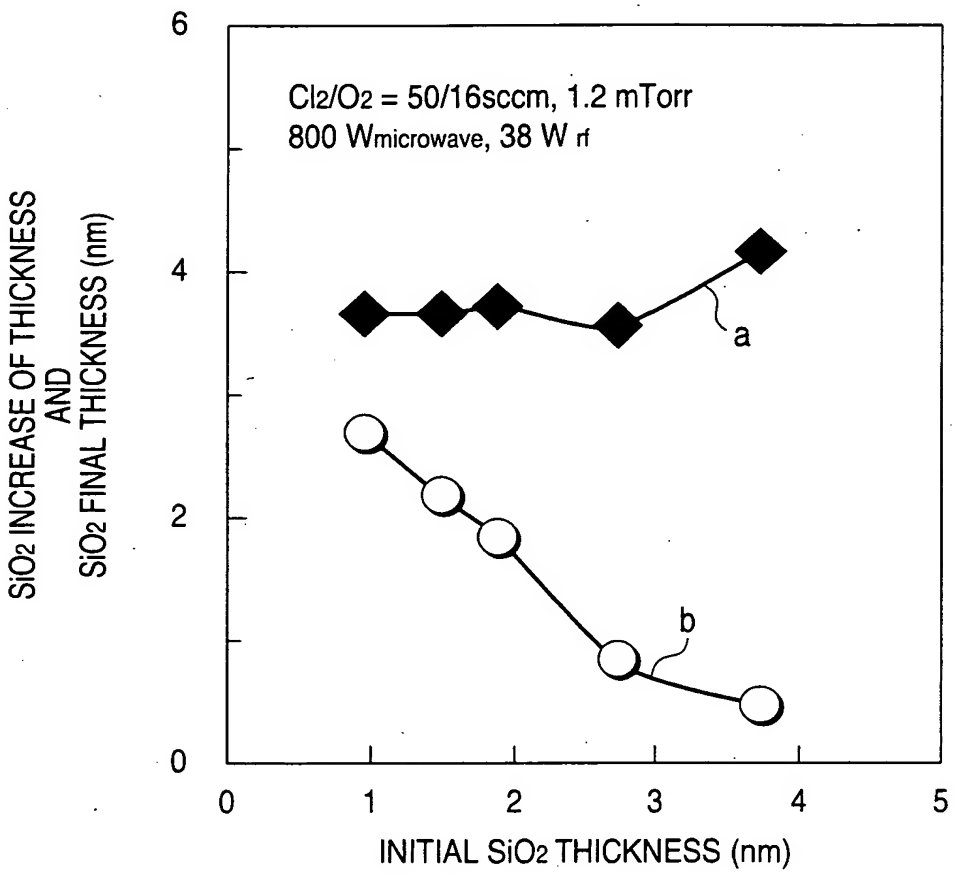

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FIG. 9

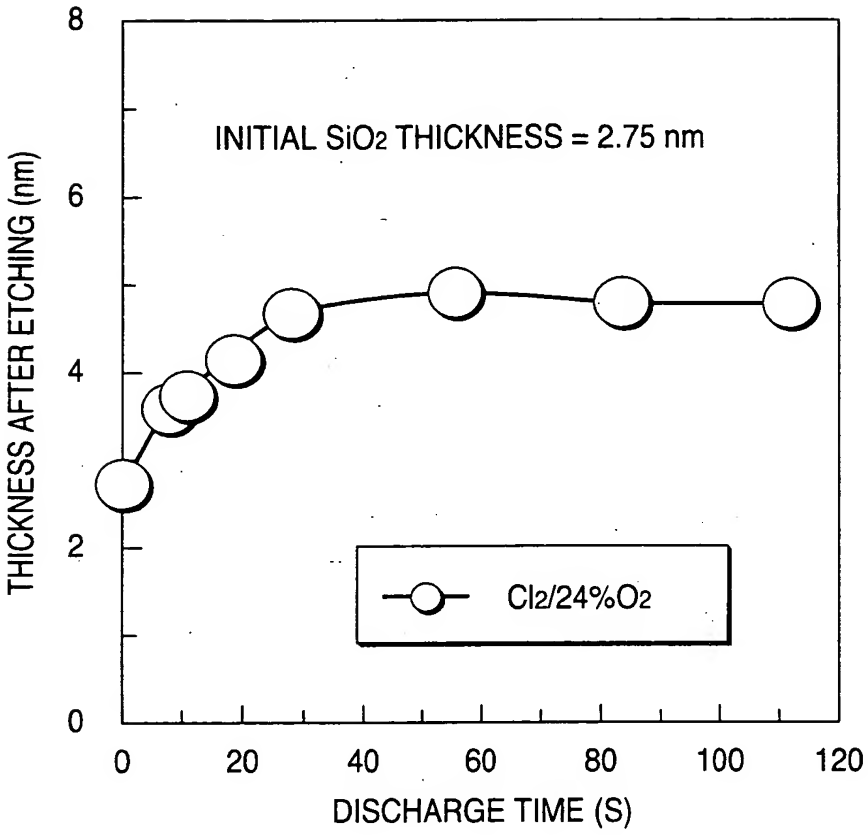


FIG. 10